Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/692,926	KEMBAIYAN, KUMAR T.	
Examiner	Art Unit	
Matthew I Smith	3672	

SEARCHED							
Class	Subclass	Date	Examiner				
175	428, 432- 435	2/27/2006	MS MS				
228	121						
76	108.4						
125	22						
420	504	1					

INI	ERFERENC	CE SEARCH	ED
Class	Subclass	Date	Examiner
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(INCLUDING SEARC	TOTICATEO	<u>, </u>
	DATE	EXMR
See search history printout	2/27/2006	/V.8 MS
Consulted: H. Dang, D. Bagnell, class 175	2/27/2006	NS MS
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